



CTL0452NS

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 20 V
- Drain-Source On-Resistance
 - $R_{DS(ON)}$ 22m Ω , at V_{GS} = 4.5V, I_{DS} = 4.5A
 - $R_{DS(ON)}$ 27m Ω , at V_{GS} = 2.5V, I_{DS} = 4.0A
- Continuous Drain Current at $T_c=25^\circ\text{C}$ I_D = 4.5A
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

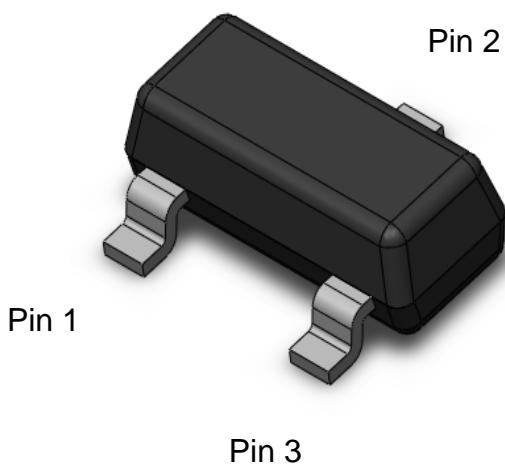
Applications

- Power Management
- Lithium Ion Battery

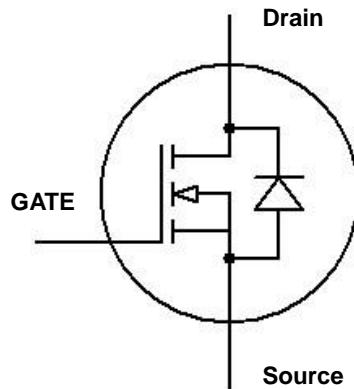
Description

The CTL0452NS uses high performance Trench Technology to provide excellent $R_{DS(ON)}$ and low gate charge which is suitable for most of the synchronous buck converter applications .

Package Outline



Schematic



Gate: Pin 1
Drain: Pin2
Source: Pin3



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Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	20	V	
V_{GS}	Gate-Source Voltage	± 8	V	
I_D	Continuous Drain Current	4.5	A	1
I_{DM}	Pulsed Drain Current	13.5	A	1
P_D	Total Power Dissipation	1.25	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\Theta JA}$	Thermal Resistance Junction-Ambient ($t=10s$)		-	175	-	°C /W	1,4



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Electrical Characteristics $T_c = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D= 250\mu\text{A}$	20	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 8\text{V}, V_{DS} = 0\text{V}$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 4.5\text{V}, I_D = 4.5\text{A}$	-	22	33	$\text{m}\Omega$	Fig 4
		$V_{GS} = 2.5\text{V}, I_D = 4.0\text{A}$	-	27	40	$\text{m}\Omega$	
$V_{GS(\text{TH})}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	0.4	-	1.0	V	Fig 5

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{DS} = 8\text{V},$ $V_{GS} = 0\text{V},$ $f=1\text{MHz}$	-	600	-	pF	Fig 3
C_{OSS}	Output Capacitance		-	81	-		
C_{RSS}	Reverse Transfer Capacitance		-	75	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 10\text{V}, V_{GS} = 4.5\text{V},$ $R_G = 6\Omega, I_D = 1\text{A}$	-	3.5	-	ns	Fig 11 & 12
T_R	Rise Time		-	23	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	39	-		
T_F	Fall Time		-	24	-		
Q_G	Total Gate Charge	$V_{DS} = 10\text{V}, V_{GS} = 4.5\text{V},$ $I_D = 4.5\text{A}$	-	7.5	-	nC	Fig 9 & 10
Q_{GS}	Gate-Source Charge		-	1.1	-		
Q_{GD}	Gate-Drain (Miller) Charge		-	2	-		



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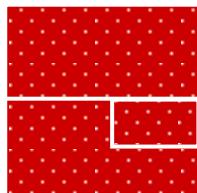
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Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_{DS}	Drain-Source Forward Voltage	$V_{GS} = 0V, I_D = 4.5A$			1.2	V	
I_S	Continuous Forward Current				4.5	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



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Typical Characteristic Curves

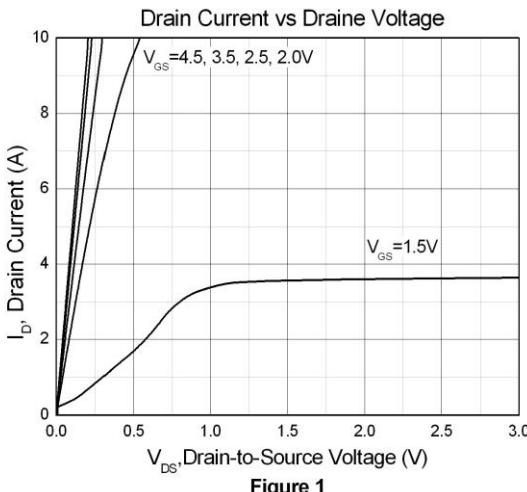


Figure 1

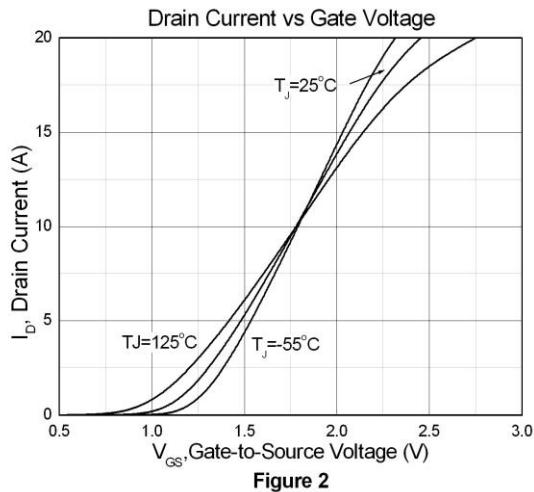


Figure 2

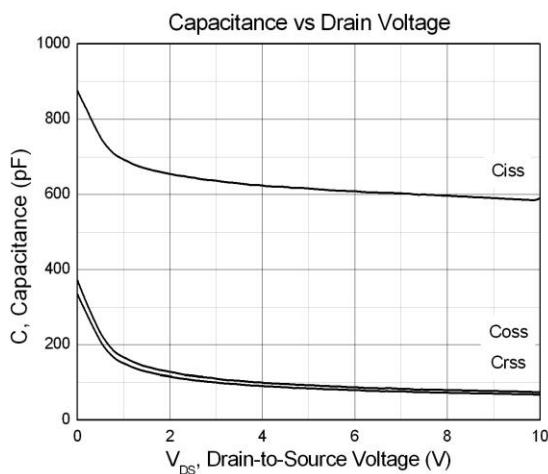


Figure 3

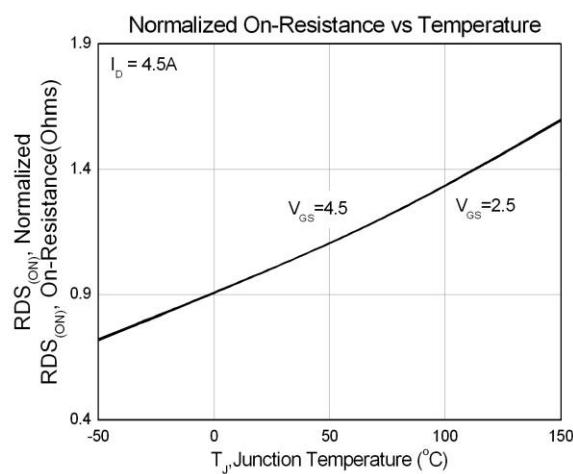


Figure 4

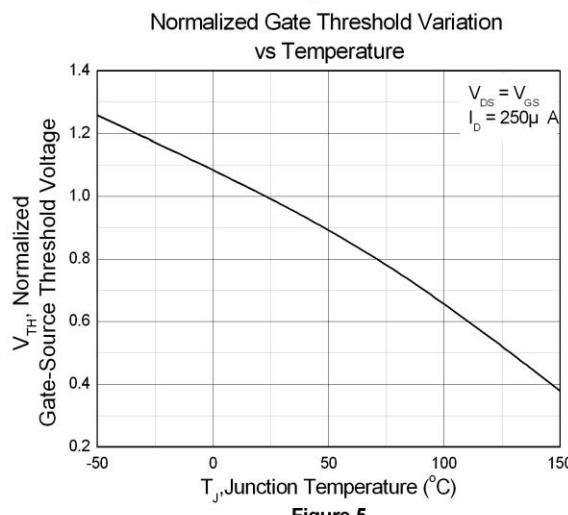


Figure 5

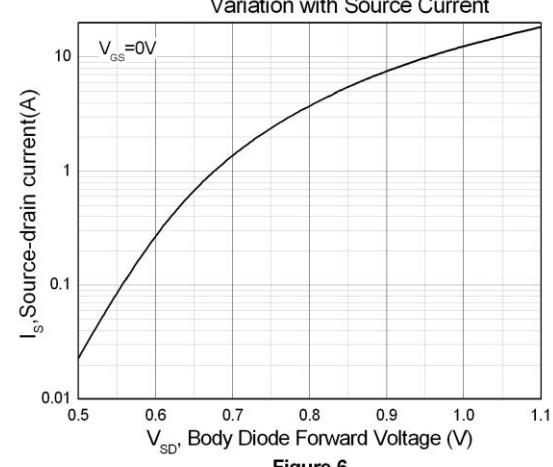
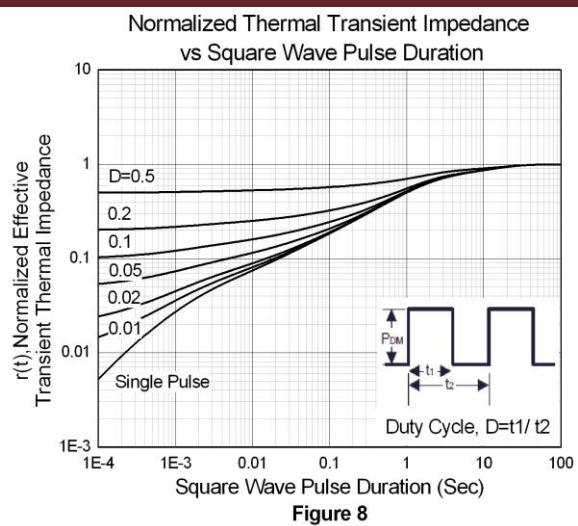
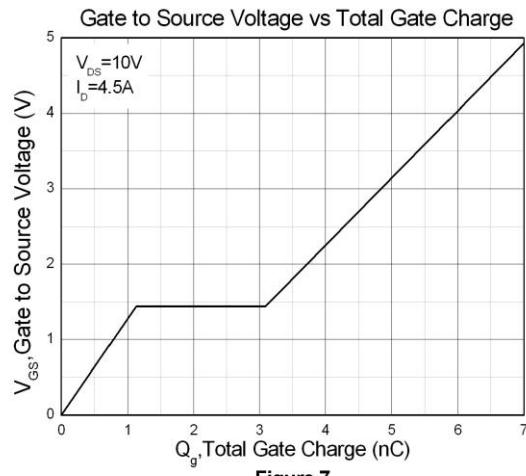


Figure 6



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Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

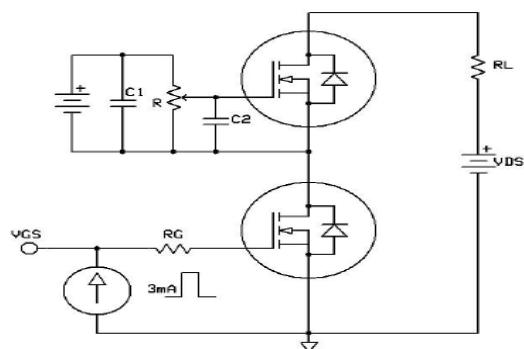


Figure 10: Gate Charge Waveform

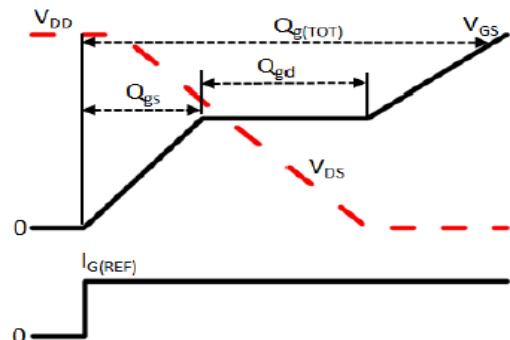


Figure 11: Switching Time Test Circuit

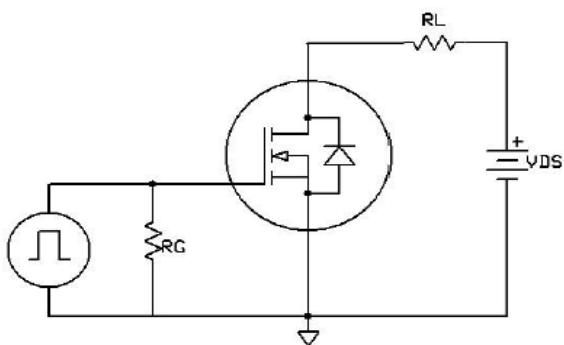
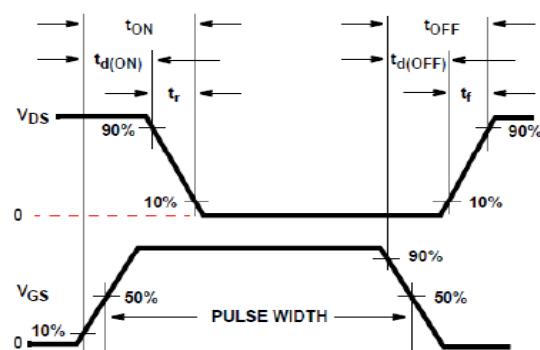


Figure 12: Switching Time Waveform

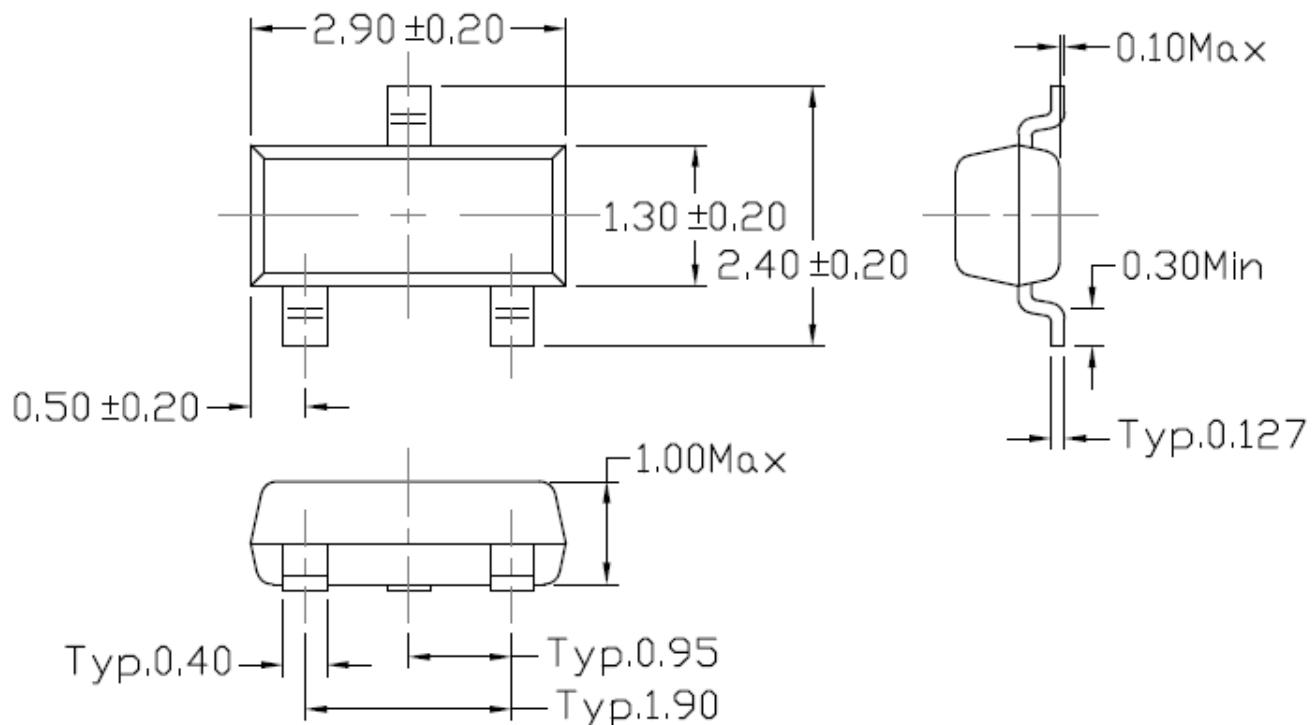




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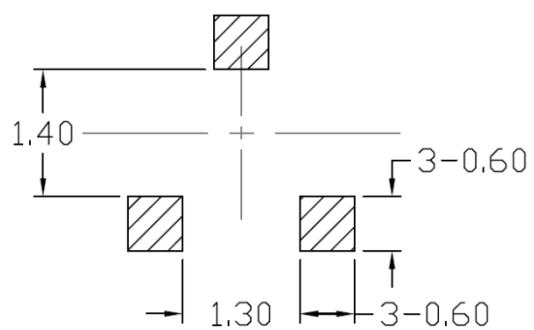
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Package Dimension



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



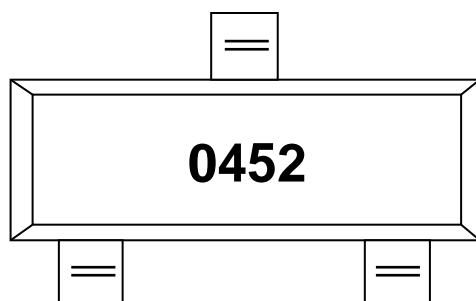
Note: Dimensions in mm



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Marking Information



0452 : Device Number

Ordering Information

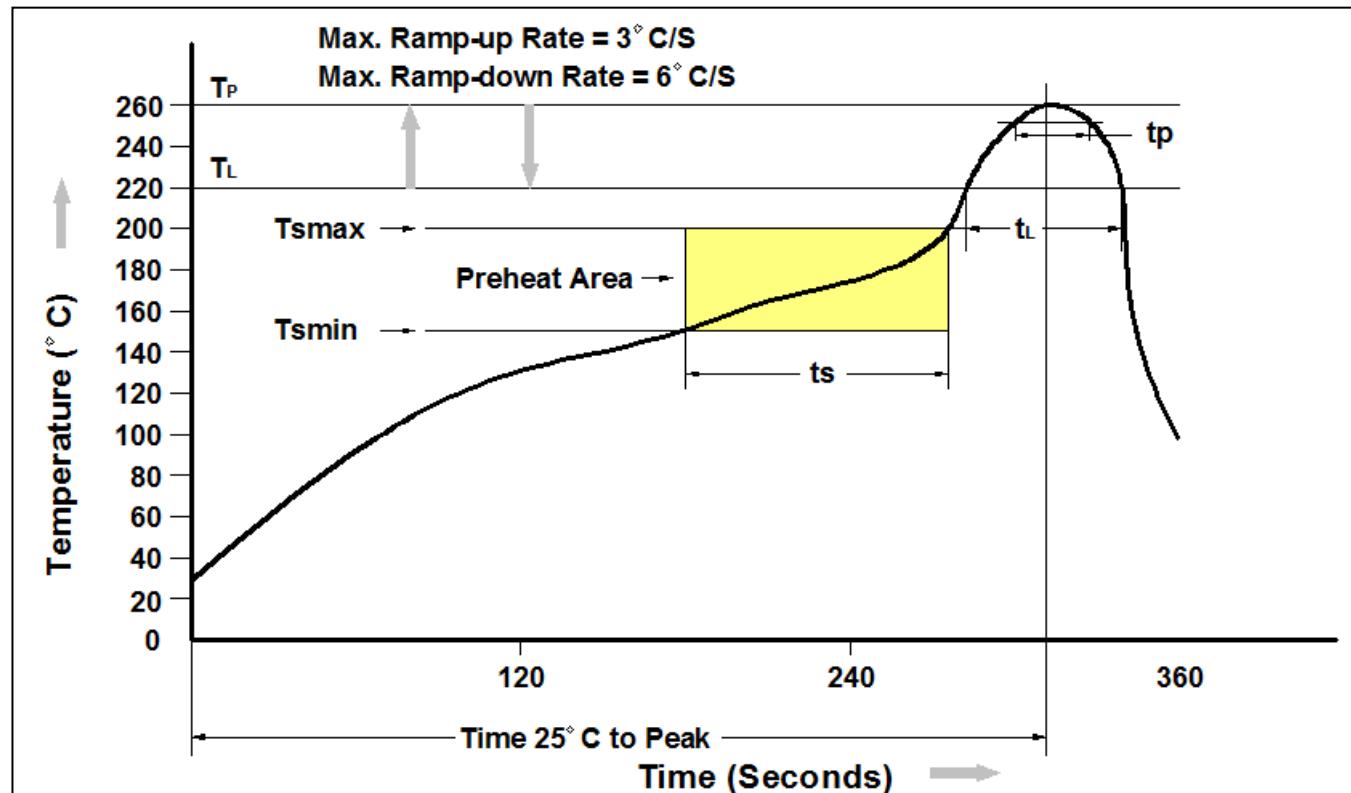
<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CTL0452NS	SOT-23 Reel	3000 pcs



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Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150°C
Temperature Max. (Tsmax)	200°C
Time (ts) from (Tsmin to Tsmax)	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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